

Search Notes

Application/Control No.

10/709,073

Examiner

Biju Chandran

Applicant(s)/Patent under
Reexamination

HSIEH, WEI-JIA

Art Unit

2835

SEARCHED

Class	Subclass	Date	Examiner
361	695	11/25/2005	BIC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
see search history		